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With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



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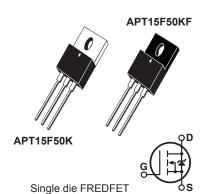




500V, 15A, 0.39Ω Max, t_{rr} ≤190ns

N-Channel FREDFET

Power MOS 8^{TM} is a high speed, high voltage N-channel switch-mode power MOSFET. This 'FREDFET' version has a drain-source (body) diode that has been optimized for high reliability in ZVS phase shifted bridge and other circuits through reduced t_{fT} , soft recovery, and high recovery dv/dt capability. Low gate charge, high gain, and a greatly reduced ratio of $C_{\text{rss}}/C_{\text{iss}}$ result in excellent noise immunity and low switching loss. The intrinsic gate resistance and capacitance of the poly-silicon gate structure help control di/dt during switching, resulting in low EMI and reliable paralleling, even when switching at very high frequency.



FEATURES

- · Fast switching with low EMI
- · Low trr for high reliability
- Ultra low C_{rss} for improved noise immunity
- · Low gate charge
- · Avalanche energy rated
- RoHS compliant

TYPICAL APPLICATIONS

- · ZVS phase shifted and other full bridge
- · Half bridge
- · PFC and other boost converter
- Buck converter
- · Single and two switch forward
- Flyback

Absolute Maximum Ratings

Symbol	Parameter	15F50K	15F50KF	Unit		
I _D	Continuous Collector Current @ T _C = 25°C	15	6.2			
	Continuous Collector Current @ T _C = 100°C	ent @ T _c = 100°C 10 3.9				
I _{DM}	Pulsed Drain Current ¹	45	18.6			
V _{GS}	Gate-Source Voltage ²	±3	V			
E _{AS}	Single Pulse Avalanche Energy ²	305		mJ		
I _{AR}	Avalanche Current, Repetitive or Non-Repetitive	7		Α		

Thermal and Mechanical Characteristics

Symbol	Parameter	Min	Тур	Max	Unit
P _D	Power Dissipation ($T_c = 25^{\circ}C$) [K]			223	W
	Power Dissipation ($T_c = 25^{\circ}C$) [KF]			37	
$R_{\theta JC}$	Junction to Case Thermal Resistance [K]			0.56	
$R_{\theta JC}$	Junction to Case Thermal Resistance [KF]			3.3	°C/W
$R_{\theta CS}$	Case to Sink Thermal Resistance, Flat, Greased Surface		0.11		
T_{J}, T_{STG}	Operating and Storage Junction Temperature Range	-55		150	°C
T _L	Soldering Temperature for 10 Seconds (1.6mm from case)			300 °C	
W _T	Doolsons Maight		0.07		oz
	Package Weight		1.2		g
Torque	Mounting Torque (TO-220 Package), 4-40 or M3 screw			10	in∙lbf
				1.1	N·m

Symbol	Parameter	Test Conditions		Min	Тур	Max	Unit
V _{BR(DSS)}	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_{D} = 28$	50μΑ	500			V
$\Delta V_{BR(DSS)} / \Delta T_{J}$	Breakdown Voltage Temperature Coefficient	Reference to 25°C, I _D = 250µA			0.60		V/°C
R _{DS(on)}	Drain-Source On Resistance [®]	V _{GS} = 10V, I _D = 7A			0.33	0.39	Ω
V _{GS(th)}	Gate-Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 0.5 \text{mA}$		2.5	4	5	V
$\Delta V_{GS(th)}/\Delta T_{J}$	Threshold Voltage Temperature Coefficient				-10		mV/°C
	Zero Gate Voltage Drain Current	$V_{DS} = 500V$ $T_{J} =$	25°C			250	μA
DSS		$V_{GS} = 0V$ $T_{J} =$	125°C			1000] μΛ
I _{GSS}	Gate-Source Leakage Current	V _{GS} = ±30V				±100	nA

Dynamic Characteristics

T_J = 25°C unless otherwise specified

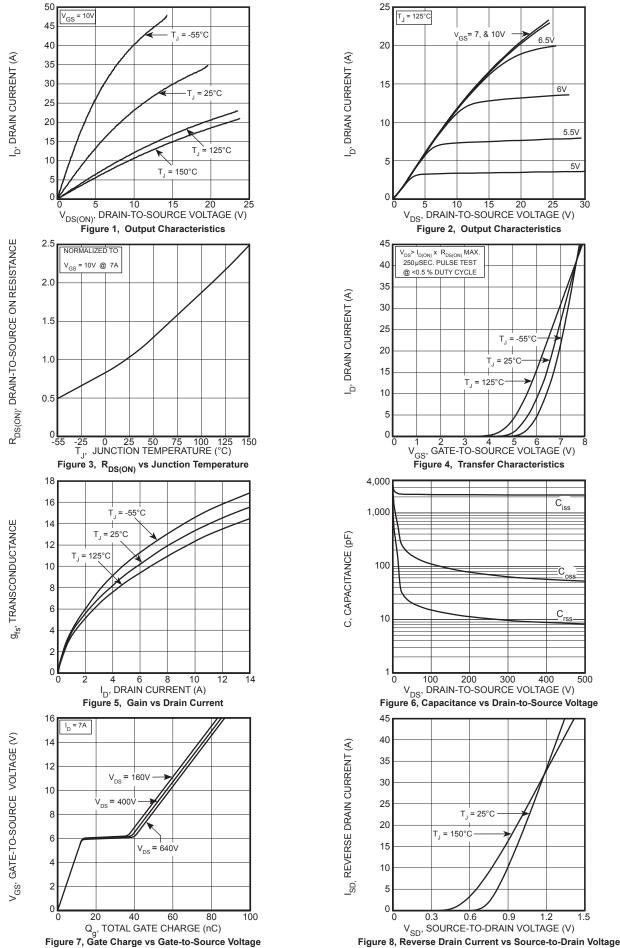
Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit	
9 _{fs}	Forward Transconductance	V _{DS} = 50V, I _D = 7A		11		S	
C _{iss}	Input Capacitance	V 0V V 0FV		2250			
C _{rss}	Reverse Transfer Capacitance	$V_{GS} = 0V, V_{DS} = 25V$ f = 1MHz		30			
C _{oss}	Output Capacitance	1 111112		240		pF	
$C^{o(cr)}$	Effective Output Capacitance, Charge Related	V = 0V V = 0V+c 222V		140			
C _{o(er)} ⑤	Effective Output Capacitance, Energy Related	V _{GS} = 0V, V _{DS} = 0V to 333V		70			
Q _g	Total Gate Charge	V 04.40V 1 7A		55			
Q_{gs}	Gate-Source Charge	$V_{GS} = 0 \text{ to } 10V, I_{D} = 7A,$		13		nC	
Q_{gd}	Gate-Drain Charge	V _{DS} = 250V		26			
t _{d(on)}	Turn-On Delay Time	Resistive Switching		10			
t _r	Current Rise Time	V _{DD} = 333V, I _D = 7A		12		ns	
t _{d(off)}	Turn-Off Delay Time	$R_{G} = 10\Omega^{\textcircled{6}}, V_{GG} = 15V$		26		115	
t _f	Current Fall Time			8			

Source-Drain Diode Characteristics

Symbol	Parameter		Test Conditions		Min	Тур	Max	Unit
	Continuous Source Current	K	MOSFET symbol showing the				15	
l I _s	(Body Diode)	KF				6.2	,	
	Pulsed Source Current (Body Diode) ^①	K	integral reverse p-n junction diode				45	A
I _{SM}		KF	(body diode)			18.6	1	
V _{SD}	Diode Forward Voltage ^③		I _{SD} = 7A, T _J = 25°			1.0	V	
	Reverse Recovery Time			T _J = 25°C			190	
t _{rr}				T _J = 125°C			340	ns
	Reverse Recovery Charge		$I_{SD} = 7A^{\textcircled{3}}$ $V_{DD} = 100V$ $di_{SD}/dt = 100A/\mu s$	T _J = 25°C		0.54		
Q _{rr}				T _J = 125°C		1.27		μC
	Reverse Recovery Current			T _J = 25°C		5.9		_
Irrm				T _J = 125°C		7.9		А
dv/dt	Peak Recovery dv/dt		$I_{SD} \le 7A$, di/dt $\le 1000A/\mu s$, $V_{DD} = 333V$, $T_{J} = 125^{\circ}C$				20 \//ns	
dv/dt							20	V/ns

- (1) Repetitive Rating: Pulse width and case temperature limited by maximum junction temperature.
- ② Starting at T_J = 25°C, L = 12.45mH, R_G = 25 Ω , I_{AS} = 7A.
- ③ Pulse test: Pulse Width < 380µs, duty cycle < 2%.
- \bigcirc C_{o(cr)} is defined as a fixed capacitance with the same stored charge as C_{OSS} with V_{DS} = 67% of V_{(BR)DSS}.
- (5) $C_{o(er)}^{(o(er))}$ is defined as a fixed capacitance with the same stored energy as $C_{OSS}^{(o(er))}$ with $V_{DS}^{(o(er))} = 67\%$ of $V_{(BR)DSS}^{(o(er))}$. To calculate $C_{o(er)}^{(o(er))}$ for any value of V_{DS} less than $V_{(BR)DSS}$, use this equation: $C_{o(er)}$ = -5.22E-8/ V_{DS} ^2 + 1.21E-8/ V_{DS} + 3.48E-11.

6 R_G is external gate resistance, not including internal gate resistance or gate driver impedance. (MIC4452) Microsemi reserves the right to change, without notice, the specifications and information contained herein.



-(0.70)

16.07 15.67

1 47 MAX

0.90 0.70

10.05 9.45

Drain

Source

1.77 (.070) 3-Plcs 1.15 (.045)

14.73 (.580) 12.70 (.500)

1.01 (.040) 3-Pics 0.83 (.033)

2.79 (.110) 2.29 (.090) 5.33 (.210) 4.83 (.190)

2.92 (.115) 2.04 (.080)

Dimensions in Millimeters and (Inches)